

Supporting Information

Dual-Emission of Silicon Quantum Dots Modified by 9-Ethylanthracene

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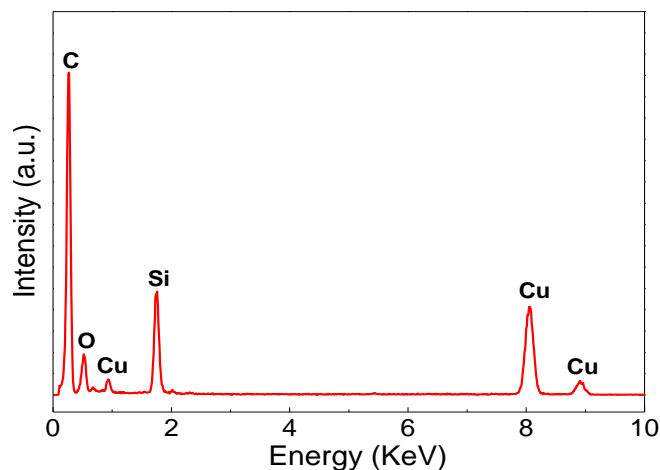


Figure S1. Energy dispersive X-ray spectroscopy (EDX) of 9-ea-Si QDs. The analysis indicates the presence of silicon, and the observation of O is due to limited surface oxidation in accordance with the IR spectrum. The containing of C can not be differentiated from the surface decyl groups and the supporting carbon film. The peaks of Cu are from the HRTEM sample grid.

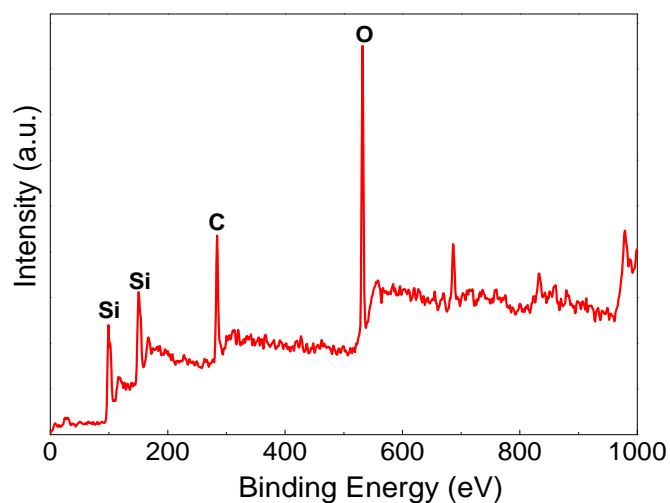


Figure S2. XPS survey spectrum of 9-ea-Si QDs.